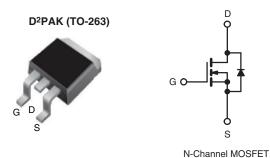


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# N-Channel 500-V (D-S) Super Junction MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	500			
R <sub>DS(on)</sub> max. at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.243		
Q <sub>g</sub> max. (nC)	66			
Q <sub>gs</sub> (nC)	8			
Q <sub>gd</sub> (nC)	14			
Configuration	Single			



#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

# ROHS COMPLIANT HALOGEN FREE

#### **APPLICATIONS**

- Computing
  - PC silver box / ATX power supplies
- Lighting
  - Two stage LED lighting
- Consumer electronics
- Applications using hard switched topologies
  - Power factor correction (PFC)
  - Two switch forward converter
  - Flyback converter
- Switch mode power supplies (SMPS)

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	500	· · · · · · · · · · · · · · · · · · ·	
Gate-Source Voltage			$V_{GS}$	± 30	V	
Continuous Drain Current (T. – 150 °C)	V <sub>GS</sub> at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	- I <sub>D</sub>	14.5	А	
Continuous Drain Current (T <sub>J</sub> = 150 °C)		T <sub>C</sub> = 100 °C		9.2		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	28		
Linear Derating Factor				1.25	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	136	mJ	
Maximum Power Dissipation			P <sub>D</sub>	156	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope $V_{DS} = 0 \text{ V to } 80 \text{ % } V_{DS}$		dV/dt	70	- V/ns		
Reverse Diode dV/dt <sup>d</sup>			27			
Soldering Recommendations (Peak Temperature) c for 10 s				300	°C	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 28.2 mH,  $R_q$  = 25  $\Omega$ ,  $I_{AS}$  = 3.1 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ , dI/dt = 100 A/ $\mu$ s, starting  $T_J = 25$  °C.

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.8	C/ VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		-			•	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA	500	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I <sub>D</sub> = 1 mA	=.	0.62	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Octo Corres Lactores		$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 30 V	-	-	± 1	μA
Zoro Cata Valtaga Drain Current	1	V <sub>DS</sub> =	= 500 V, V <sub>GS</sub> = 0 V	=.	-	10	μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 400 \	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	25	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	$I_D = 7.5 A$	-	0.243	0.280	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	= 30 V, I <sub>D</sub> = 7.5 A	-	3.9	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 V$ ,	-	1162	-	
Output Capacitance	C <sub>oss</sub>		$V_{DS} = 100 \text{ V},$	=.	51	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		f = 1 MHz	-	7	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	- V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		-	55	-	pF -
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	164	-	
Total Gate Charge	$Q_g$			-	33	66	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_{D} = 7.5 \text{ A}, V_{DS} = 400 \text{ V}$		8	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	14	-	1
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 400 V, I <sub>D</sub> = 12 A,		-	15	30	-
Rise Time	t <sub>r</sub>			-	24	48	
Turn-Off Delay Time	t <sub>d(off)</sub>	V <sub>GS</sub> :	= 10 V, $R_g = 9.1 \Omega$	=.	34	68	ns
Fall Time	t <sub>f</sub>		1		18	36	]
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	0.85	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the		-	-	14.5	
Pulsed Diode Forward Current	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	28	A
Diode Forward Voltage	V <sub>SD</sub>	$T_J = 25 ^{\circ}\text{C},  I_S = 7.5  \text{A},  V_{GS} = 0  \text{V}$		-	-	1.2	٧
Reverse Recovery Time	t <sub>rr</sub>				265	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 7.5 A, dI/dt = 100 A/ $\mu$ s, V <sub>R</sub> = 25 V		-	3.2	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	23	-	Α

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

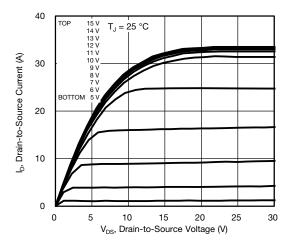


Fig. 1 - Typical Output Characteristics

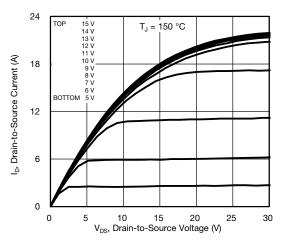


Fig. 2 - Typical Output Characteristics

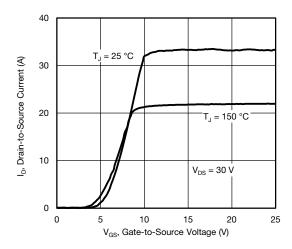


Fig. 3 - Typical Transfer Characteristics

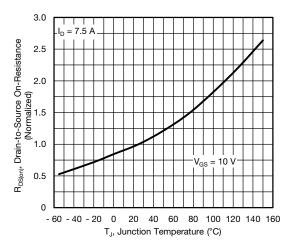


Fig. 4 - Normalized On-Resistance vs. Temperature

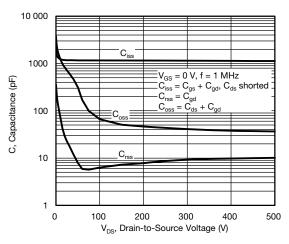


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

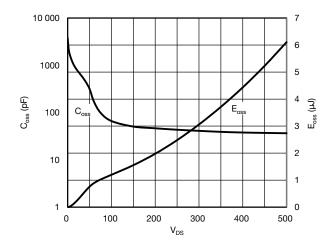


Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$ 

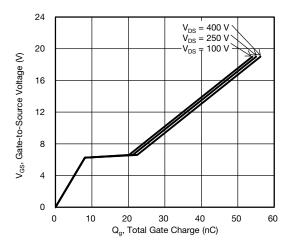


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

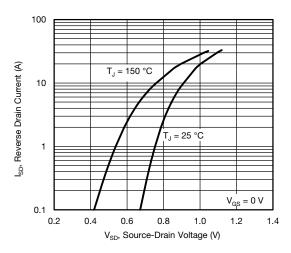


Fig. 8 - Typical Source-Drain Diode Forward Voltage

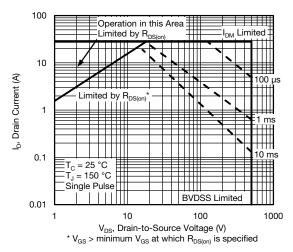


Fig. 9 - Maximum Safe Operating Area

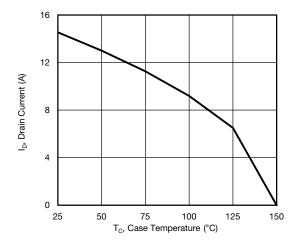


Fig. 10 - Maximum Drain Current vs. Case Temperature

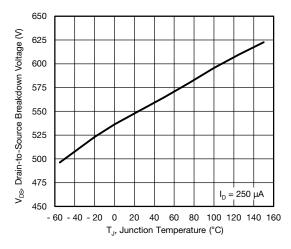


Fig. 11 - Temperature vs. Drain-to-Source Voltage

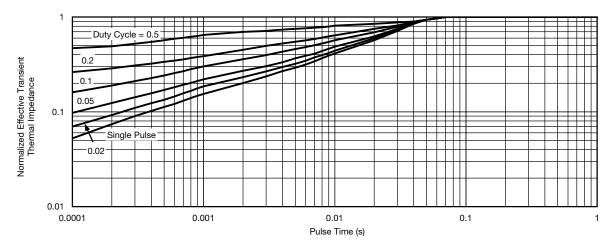


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

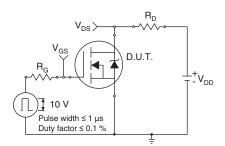


Fig. 13 - Switching Time Test Circuit

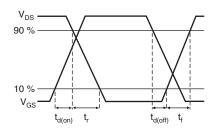


Fig. 14 - Switching Time Waveforms

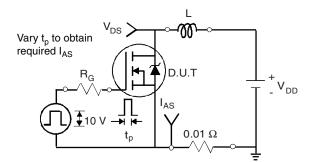


Fig. 15 - Unclamped Inductive Test Circuit

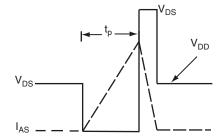


Fig. 16 - Unclamped Inductive Waveforms

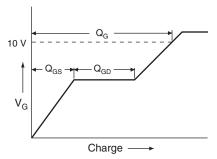


Fig. 17 - Basic Gate Charge Waveform

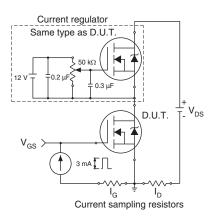
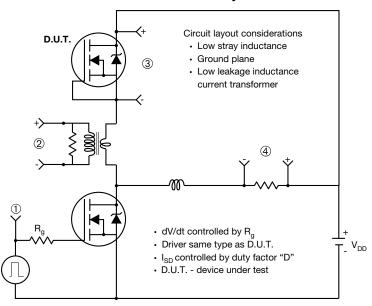


Fig. 18 - Gate Charge Test Circuit

### Peak Diode Recovery dV/dt Test Circuit



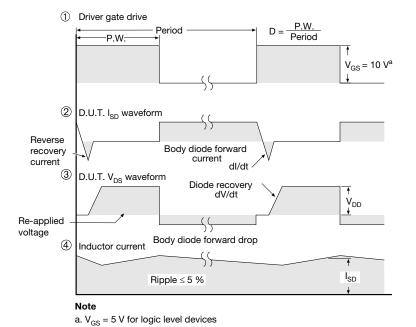
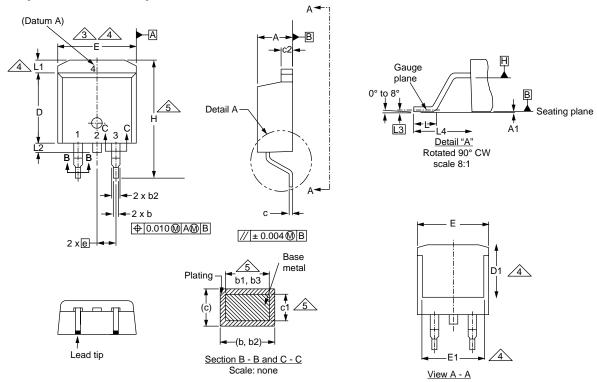


Fig. 19 - For N-Channel

### **TO-263AB (HIGH VOLTAGE)**



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
Е	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
Н	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010	BSC
L4	4.78	5.28	0.188	0.208

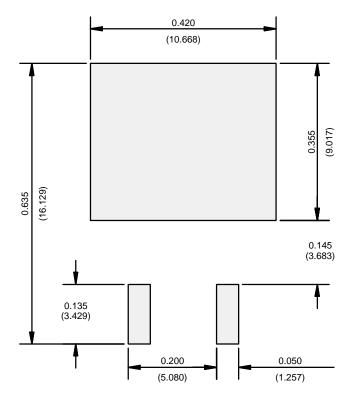
DWG: 5970

ECN: S-82110-Rev. A, 15-Sep-08

#### Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.

## RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)





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